

SEMICAPS SOM 2000

UPRIGHT TESTER-DOCKED SCANNING OPTICAL MICROSCOPE SYSTEM



Features

- ~ Adaptable to various ATE
- ~ Ease of system portability
- ~ High resolution stage with 20nm resolution and 0.5 μ m repeatability
- ~ High resolution laser scanner with up to 2Kx2K scan resolution
- ~ High power NIR lasers compatible
- ~ Multi-laser induced techniques system
- ~ Multi-detector capability: Si-CCD, InGaAs and InSb
- ~ Refractive & diffractive Solid Immersion Lens (SIL) option
- ~ Thermal management option
- ~ CAD interface option
- ~ Laser marker option

